



DQ Check for CERN Test Beam 2007 data

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Outline

- Statistic
- Ecal Response: Longitudinal Profile, Linearity & Resolution
- Problems & Noise Patterns observed in TB data

Statistic

- Scan over 1000 runs on /grid/calice/tbcern/rec/monitor-cern07: (from run 330400 - run 331568, currently about 100 runs failed or missed in grid job submission)
- About 90 electron runs, 80 electron-pion mixed run and 160 pion runs are marked as Most valuable runs, with statistic > 100k per run. (A few runs with statistic < 100k was also marked as most valuable run for those run could combine together with other runs with same beam configuration to gain enough statistic).

Ecal Response: Longitudinal Profile

	0 Degree	10 Degree	20 Degree
50GeV	330428	330986	331211
40GeV	331315	330990	331207
30GeV	330430	330993	331204
25GeV	330431	330994	331202
20GeV	330432	330995	331198
15GeV	330433	330996	331194
12GeV		331015	331126
10GeV		331012	331128

A set of most valuable electron runs are selected: with beam aim at wafer center.

Only the default cut (energy>0.5 mip) of reconstruction is applied

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Normal inject beam:



10° impact:



20° impact:



A Gaussian fit on the main peak of ECAL energy spectrum



Linearity: Without Any Cleaning & selection:

1GeV ~ 269 mips

(>233 mips (the value for last TB experiment) for different cut applied?)





Linearity: overlay for 3 different inject angle



Resolution:

Without Any Cleaning & selection:

 χ^2 / ndf

0.28

0.32

0.3

Prob

p0

p1

0.22 0.24 0.26

$\sigma(E) \sim 0.2 \text{sqrt}(E)$

Ecal Energy Resolution Vary with Beam Energy, 10Deg

10[°]

us.065

0.05

0.045

0.04

0.035

0.025

0.03

0.14

0.16

0.18

0.2



Resolution accuracy: overlay for 3 different inject angle



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Noise & Problem Patterns observed

- Wafer Gap effect: Bump & Double bump in ecal energy spectrum
- Ecal: less hit in ecal last layer: almost affect every Pion Run (and high energy electron runs)
- Low energy noise in several ecal layer
- Disconnect of Up PCB in ecal layer 27
- Time dependent Noise
- Beam unstable or went off during the run

Bump pattern is observed for runs with beam aim at the wafer gap:



Double bump pattern is observed for run with beam aim at the wafer corner:

Some events loose more energy!



Less hits in ecal last layer:



Many dead Cells and a whole dead half wafer on Ecal last layer:

htemp

Plots draw from first 120k events of Run 330733



Low energy noise:

Amplitude for corresponding Layer in Longitudinal profile in hit increases a lot while Longitudinal profile in energy Does not change much



For run 331354-331389, the Up PCB of layer 27 seems not **Connect!**



Time dependent noise: some layer behavior anomaly during the run

- ECAL
 - Layer 10: 330877...
 - Layer 11: 330330, 330950...
 - Layer 26: 331131, 1134, 1173, 1175, 1065, 1246, 1221, 1251...
 - Layer 29: 330732...
- HCAL
 - Layer 6: 331286...
 - Layer 13: 330839, 1143, 1198, 1244, 1246, 1258, 1308...
 - Layer 32: 330411, 0461, 0475, 0590, 0606, 0733, 0808, 0826, 0853, 0937, 0947...

Noisy region could be located to a half wafer (one chip):



Or the whole PCB



Similar pattern could be observed in HCAL



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Beam was quite stable during our data taking, but sometime it went off during the run:



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Summary

- Large statistic of high-quality test beam data had been collected;
- Energy resolution linearity and accuracy look consistent with our last test beam data result;
- Many new noisy pattern observed and requires carefully treatment

Back Up





Funny pattern: Summer students change the beam file

30 layer

25

20

15

10

5

0

20



5000

Total Energy Deposite in Ecal: Run 330920, Summer students playing the beam

TotalEcalEnergy

102471

1550

1262

Entries

Mean

RMS

Run 331243: large noise in both ecal and hcal, beam off during the run;



Run 331069: Many Noise Cells in Ecal;

